### **INTEGRATED CIRCUITS**

# DATA SHEET



**74F109**Positive J-K positive edge-triggered flip-flops

Product specification

1990 Oct 23

IC15 Data Handbook





### Postive J-K positive edge-triggered flip-flops

74F109

#### **FEATURE**

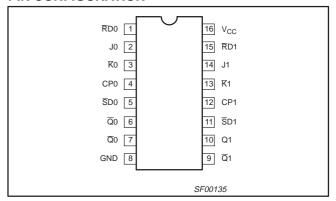
• Industrial temperature range available (-40°C to +85°C)

### **DESCRIPTION**

The 74F109 is a dual positive edge-triggered JK-type flip-flop featuring individual J,  $\overline{K}$ , clock, set, and reset inputs; also true and complementary outputs. Set ( $\overline{SD}$ ) and reset ( $\overline{RD}$ ) are asynchronous active low inputs and operate independently of the clock ( $\overline{CP}$ ) input. The J and  $\overline{K}$  are edge-triggered inputs which control the state changes of the flip-flops as described in the function table. Clock triggering occurs at a voltage level and is not directly related to the transition time of the positive-going pulse. The J and  $\overline{K}$  inputs must be stable just one setup time prior to the low-to-high transition of the clock for predictable operation. The J $\overline{K}$  design allows operation as a D flip-flop by tying J and  $\overline{K}$  inputs together. Although the clock input is level sensitive, the positive transition of the clock pulse between the 0.8V and 2.0V levels should be equal to or less than the clock to output delay time for reliable operation.

TYPE	TYPICAL f <sub>max</sub>	TYPICAL SUPPLY CURRENT (TOTAL)
74F109	125MHz	12.3mA

### **PIN CONFIGURATION**





#### ORDERING INFORMATION

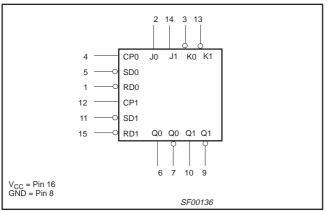
	ORDER	CODE	
DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ , $T_{amb} = 0^{\circ}C$ to $\pm 70^{\circ}C$	INDUSTRIAL RANGE $V_{CC}$ = 5V $\pm$ 10%, $T_{amb}$ = $-40^{\circ}$ C to $+85^{\circ}$ C	PKG DWG #
16-pin plastic DIP	N74F109N	I74F109N	SOT38-4
16-pin plastic SO	N74F109D	I74F109D	SOT109-1

### INPUT AND OUTPUT LOADING AND FAN OUT TABLE

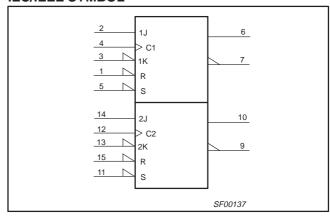
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
J0, J1	J inputs	1.0/1.0	20μA/0.6mA
₹0, ₹1	K inputs	1.0/1.0	20μA/0.6mA
CP0, CP1	Clock inputs (active rising edge)	1.0/1.0	20μA/0.6mA
SD0, SD1	Set inputs (active Low)	1.0/3.0	20μA/1.8mA
RD0, RD1	Reset inputs (active Low)	1.0/3.0	20μA/1.8mA
Q0, Q1, Q0, Q1	Data outputs	50/33	1.0mA/20mA

**NOTE:** One (1.0) FAST unit load is defined as: 20μA in the High state and 0.6mA in the Low state.

### **LOGIC SYMBOL**



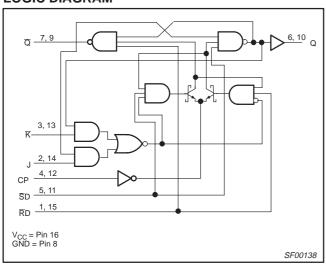
### **IEC/IEEE SYMBOL**



### Postive J-K positive edge-triggered flip-flops

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### **LOGIC DIAGRAM**



### **FUNCTION TABLE**

	II	NPUTS	3		OUTF	PUTS	OPERATING MODE		
SD	RD	СР	J	K	Q	Q	OI ERATING MODE		
L	Н	Х	Х	Х	Н	L	Asynchronous set		
Н	L	Х	Х	Х	L	Н	Asynchronous reset		
L	L	Х	Х	Х	Н	Н	Undetermined*		
Н	Н	1	Х	Х	q	q	Hold		
Н	Н	1	h	I	q	q	Toggle		
Н	Н	1	h	h	Н	L	Load "1" (set)		
Н	Н	1	Ι	I	L	Н	Load "0" (reset)		
Н	Н	<u> </u>	Ī	h	q	q	Hold 'no change"		

### NOTES:

H = High-voltage level

High-voltage level one setup time prior to low-to-high clock transition

Low-voltage level

Low-voltage level one setup time prior to low-to-high clock transition

Lower case indicate the state of the referenced output prior to the low-to-high clock transition

Don't care

Low-to-high clock transition Not low-to-high clock transition

Both outputs will be high if both SD and RD go low

### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage		-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage		-0.5 to +7.0	V
I <sub>IN</sub>	Input current		−30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in High output state		−0.5 to V <sub>CC</sub>	V
I <sub>OUT</sub>	Current applied to output in Low output state		40	mA
_	Operating free circumparature range	Commercial range	0 to +70	°C
T <sub>amb</sub>	Operating free-air temperature range	Industrial range	-40 to +85	°C
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C

### RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER			LIMITS		UNIT
STIMBUL	PARAMETER		MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		4.5	5.0	5.5	V
V <sub>IN</sub>	High-level input voltage		2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V	
I <sub>IK</sub>	Input clamp current				-18	mA
I <sub>OH</sub>	High-level output current				-1	mA
I <sub>OL</sub>	Low-level output current				20	mA
_	Operating free-air temperature range	Commercial range	0		+70	°C
lamb	Operating free-air temperature range	Industrial range	-40		+85	°C

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### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST COL	NDITIONS <sup>1</sup>			LIMITS		UNIT
STWIBUL	PARAMETER		TEST CON	ADITIONS.		MIN	TYP <sup>2</sup>	MAX	UNIT
	Liab laval autout valta sa		$V_{CC} = MIN, V_{II} = MAX.$	I MAN	±10%V <sub>CC</sub>	2.5			V
V <sub>OH</sub>	High-level output voltage		$V_{CC} = MIN, V_{IL} = MAX,$ $V_{IH} = MIN$	I <sub>OH</sub> = MAX	±5%V <sub>CC</sub>	2.7	3.4		V
.,	Lava lava Lava lava lava lava lava		$V_{CC} = MIN, V_{IL} = MAX,$	I <sub>OL</sub> = MAX	±10%V <sub>CC</sub>		0.30	0.50	V
V <sub>OL</sub>	Low-level output voltage		V <sub>IH</sub> = MIN		±5%V <sub>CC</sub>		0.30	0.50	V
V <sub>IK</sub>	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$			-0.73	-1.2	V	
II	Input current at maximum in	put voltage	$V_{CC} = MAX, V_I = 7.0V$					100	μΑ
I <sub>IH</sub>	High-level input current		$V_{CC} = MAX, V_I = 2.7V$					20	μΑ
	Low lovel input surrent	J, K̄, CPn	$V_{CC} = MAX, V_I = 0.5V$					-0.6	mA
l <sub>IL</sub>	Low-level input current SDn, RDn		$V_{CC} = MAX, V_I = 0.5V$					-1.8	mA
Ios	Short-circuit output current <sup>3</sup>		$V_{CC} = MAX$	4_	-60		-150	mA	
Icc	Supply current <sup>4</sup> (total)		$V_{CC} = MAX$	4.3	J. /14		12.3	17	mA

#### NOTES:

- 1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>amb</sub> = 25°C.
   Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

  4. Measure  $I_{CC}$  with the clock input grounded and all outputs open, then with Q and  $\overline{Q}$  outputs high in turn.

### AC ELECTRICAL CHARACTERISTICS

				LIMITS								
SYMBOL	PARAMETER	TEST CONDITION	$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF$ $R_{L} = 500\Omega$			T <sub>amb</sub> = 0°0 C <sub>L</sub> =	0V ± 10% C to +70°C 50pF 500Ω	V <sub>CC</sub> = +5. T <sub>amb</sub> = -40° C <sub>L</sub> = R <sub>L</sub> =	UNIT			
			MIN	TYP	MAX	MIN	MAX	MIN	MAX			
f <sub>MAX</sub>	Maximum clock frequency	Waveform 1	90	125		90		90		MHz		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CPn to Qn or Qn	Waveform 1	3.8 4.4	5.3 6.2	7.0 8.0	3.8 4.4	8.0 9.2	3.8 4.4	9.0 9.2	ns		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay SDn, RD to Qn or Qn	Waveform 2, 3	3.2 3.5	5.2 7.0	7.0 9.0	3.2 3.5	8.0 10.5	2.8 3.5	9.0 10.5	ns		

### **AC SETUP REQUIREMENTS**

						LI	MITS			
SYMBOL	PARAMETER	TEST CONDITION	$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF$ $R_{L} = 500\Omega$			T <sub>amb</sub> = 0°0 C <sub>L</sub> =	0V ± 10% C to +70°C 50pF 500Ω	V <sub>CC</sub> = +5. T <sub>amb</sub> = -40° C <sub>L</sub> = R <sub>L</sub> =	UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>su</sub> (H) t <sub>su</sub> (L)	Setup time, high or low Dn to CPn	Waveform 1	3.0 3.0			3.0 3.0		3.0 3.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, high or low Dn to CPn	Waveform 1	1.0 1.0			1.0 1.0		1.0 1.0		ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	CP pulse width, high or low	Waveform 1	4.0 5.0			4.0 5.0		4.0 5.0		ns
t <sub>w</sub> (L)	$\overline{S}$ Dn or $\overline{R}$ Dn pulse width, low	Waveform 2	4.0			4.0		4.0		ns
t <sub>rec</sub>	Recovery time SDn or RDn to CP	Waveform 3				2.0		2.0		ns

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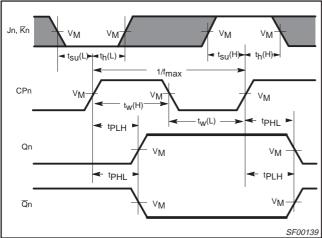
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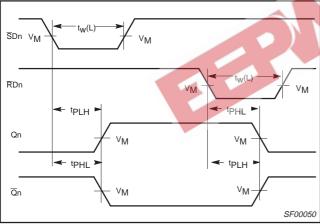
### **AC WAVEFORMS**

For all waveforms,  $V_M = 1.5V$ .

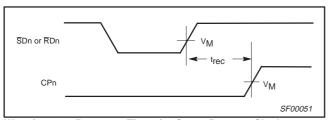
The shaded areas indicate when the input is permitted to change for predictable output performance.



Waveform 1. Propagation Delay for Data to Output, Data Setup Time and Hold Times, and Clock Width,and Maximum Clock Frequency



Waveform 2. Propagation Delay for Set and Reset to Output, Set and Reset Pulse Width

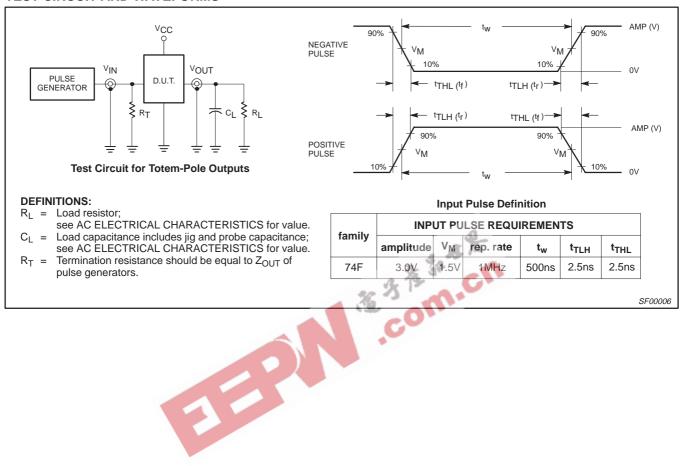


Waveform 3. Recovery Timer for Set or Reset to Clock

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### **TEST CIRCUIT AND WAVEFORMS**

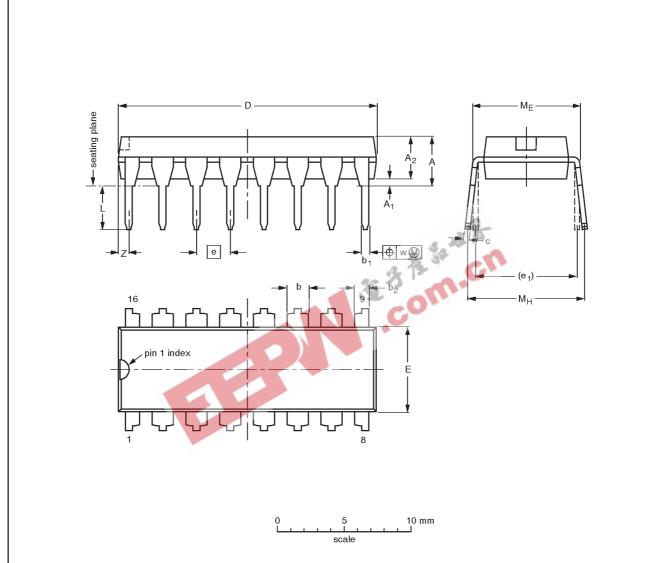


# Positive J-K positive edge-triggered flip-flops

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### DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	b <sub>2</sub>	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	e <sub>1</sub>	L	ME	Мн	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
SOT38-4					<del>92-11-17</del> 95-01-14

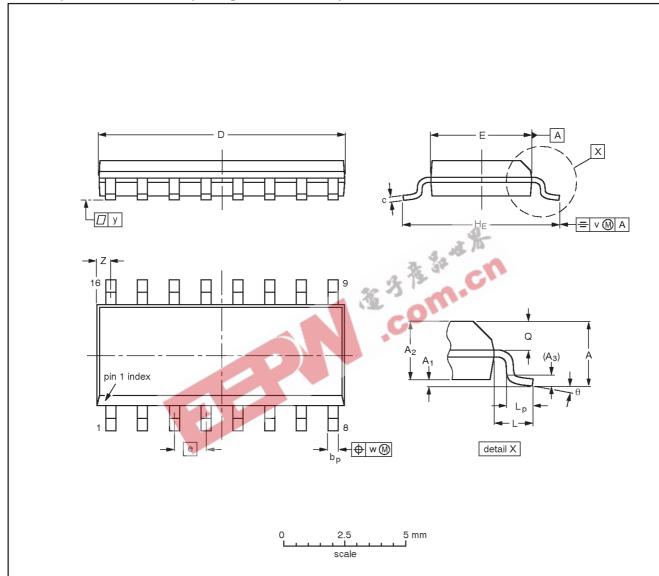
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# Positive J-K positive edge-triggered flip-flops

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### SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	10.0 9.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01			0.39 0.38	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.020	0.01	0.01	0.004	0.028 0.012	0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT109-1	076E07S	MS-012AC				<del>95-01-23</del> 97-05-22

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### **NOTES**



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### Positive J-K positive edge-triggered flip-flops

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### Data sheet status

Data sheet status	Product status	Definition [1]	
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.	
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.	
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.	

<sup>[1]</sup> Please consult the most recently issued datasheet before initiating or completing a design.

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